Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
09/916,517	LEE, TAE WON
Examiner	Art Unit
Trang U. Tran	2614

	SEAR	CHED	l		
Class	Subclass	Di	Date Examiner		
348	725-726	12/22	/2005	т	т
	731-733				
	570				
	21, 674				
342	359				
	74-75				
	77				
455	67.1				
	67.2-67.7				
	25, 226.1				
	226.2				
	3.02				
725	72				
375	232				1

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEA (INCLUDING	RCH NOTI)
-		DATE	EXMR
348		12/22/2005	ττ
Nguyen Vo 455		12/22/2005	тт